Power MOSFET, Dual P-Channel

-40 V, -20 A, 12.5 m Ω

Features

- Small Footprint (5x6 mm) for Compact Design
- Low R_{DS(on)} to Minimize Conduction Losses
- Low QG and Capacitance to Minimize Driver Losses
- Wettable Flanks for Enhanced Optical Inspection
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Parameter		Symbol	Value	Unit		
Drain-to-Source Voltage		VDSS	-40	V		
Gate-to-Source Voltage			Vgs	±16	V	
Continuous Drain		T _C = 25°C		-60.8	_	
Current R _{θJC} (Notes 1, 3)	Steady State	T _C = 100°C	I _D	-43.0	Α	
Power Dissipation R _{θJC} (Note 1)		T _C = 25°C	_	75		
		T _C = 100°C	P _D	37.5	W	
Continuous Drain Current R _{θJA} (Notes 1, 2, 3)	Steady State	T _C = 25°C		-12.2		
		T _C = 100°C	l _D	-8.6	Α	
Power Dissipation R _{θJA} (Notes 1 & 2)		T _C = 25°C	_	3.0	W	
		T _C = 100°C	P _D	1.5		
Pulsed Drain Current $T_C = 25^{\circ}C, t_p = 10 \mu s$			Ірм	-281	А	
Operating Junction and Storage Temperature			TJ, Tstg -55 to +175		°C	
Source Current (Body Diode)			I _S	-20	Α	
Single Pulse Drain-to-Source Avalanche Energy (IL(pk) = -19)			Eas	90	mJ	
Lead Temperature for Soldering Purposes (1/83 from case for 10 s)			T _L	260	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{ heta JC}$	2	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	50	°C/W

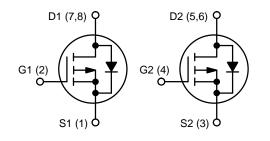
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface–mounted on FR4 board using a 650 mm², 2 oz. Cu pad.
- 3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



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V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
-40 V	12.5 mΩ @ –10 V	–20 A
	19.5 mΩ @ –4.5 V	





ORDERING INFORMATION

See detailed ordering, marking and shipping information on page 3 of this data sheet.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
Off Characteristics	•					•	•
Drain to Source Breakdown Voltage	V(BR)DSS	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$		-40			٧
Drain-to-Source Breakdown Voltage Temperature Coefficient	V(BR)DSS/ T _J				21		mV/°C
Zero Gate Voltage Drain Current	IDSS	V _{GS} = 0 V, V _{DS} = -40 V	T _J = 25°C			-1	μΑ
			T _J = 175°C			-1	mA
Zero Gate Voltage Drain Current	Igss	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 16 \text{ V}$				±100	nA
On Characteristics (Note 4)					U.	I.	
Gate Threshold Voltage	VGS(TH)	$V_{GS} = V_{DS}, I_D = -250 \mu A$		-1	-1.8	-3	٧
Threshold Temperature Coefficient	VGS(TH)/TJ				-5.5		mV/°C
Drain-to-Source On Resistance	RDS(on)	V _{GS} = -10 V	I _D = -20 A		10.4	12.5	mΩ
		V _{GS} = -4.5 V	I _D = -10 A		14.6	19.5	
Charges, Capacitances & Gate Resis	stance			<u> </u>	1	<u> </u>	<u> </u>
Input Capacitance	Ciss	V _{GS} = 0 V, f = 1 MHz, V _{DS} = -20 V			2370		pF
Output Capacitance	Coss				940		pF
Reverse Transfer Capacitance	Crss]			40		pF
Gate Resistance	R _g	V _{GS} = 0.5 V, f = 1 MHz			17		Ω
Total Gate Charge	QG(TOT)	$V_{GS} = -10 \text{ V}, V_{DS} = -32 \text{ V}; I_D = -20 \text{ A}$			33		nC
		$V_{GS} = -4.5V$, $V_{DS} = -32 V$; $I_D = -20 A$			13		
Threshold Gate Charge	Qg(th)	V _{GS} = 0 to −1 V			2		
Gate to Source Gate Charge	Qgs	V _{DD} = -20 V, I _D = -20 A			7		
Gate to Drain "Miller" Charge	Qgd				4		
Plateau Voltage	VGP				-4		V
Switching Characteristics	•				•		•
Turn-On Delay Time	td(ON)	$V_{DD} = -20 \text{ V}, I_{D} = -20 \text{ A}, V_{GS} = -10 \text{ V},$ $R_{GEN} = 6 \Omega$			8		ns
Turn-On Rise Time	t _r				21		ns
Turn-Off Delay Time	td(OFF)				120		ns
Turn-Off Fall Time	t _f				34		ns
Drain-Source Diode Characteristics							•
Source to Drain Diode Voltage	VsD I _{SD} = -20 A, V _{GS} = 0 V		= 0 V		-0.9	-1.25	V
		I _{SD} = -10 A, V _{GS}	= 0 V		-0.83	-1.2	V
Reverse Recovery Time	TRR	$V_{GS} = 0 \text{ V}, dI_{SD}/dt = 100 \text{ A/us}, I_{S} = -20 \text{ A}$			46		ns
Charge Time	t _a				22		1
Discharge Time	t _b				24		1
Reverse Recovery Charge	Qrr				37		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width $\leq 300~\mu s$, duty cycle $\leq 2\%$ 5. Switching characteristics are independent of operating junction temperatures.

ORDERING INFORMATION

Device	Device Marking	Package	Shipping [†]
FDWS9520L-F085	FDWS9520L	PQFN8 5x6, 12.7P (Pb–Free, Halogen Free)	3,000 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D

TYPICAL CHARACTERISTICS

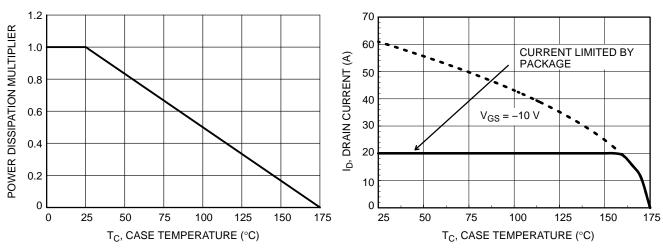


Figure 1. Normalized Power Dissipation vs.

Case Temperature

Figure 2. Maximum Continuous Drain Current vs. Case Temperature

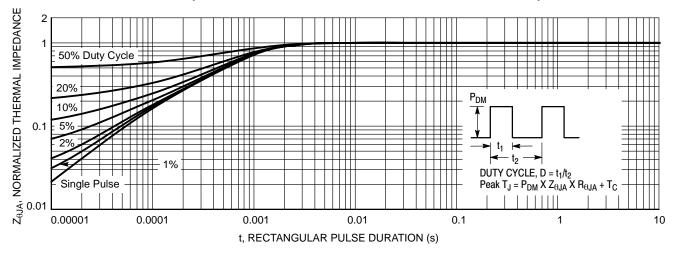


Figure 3. Normalized Maximum Transient Thermal Impedance

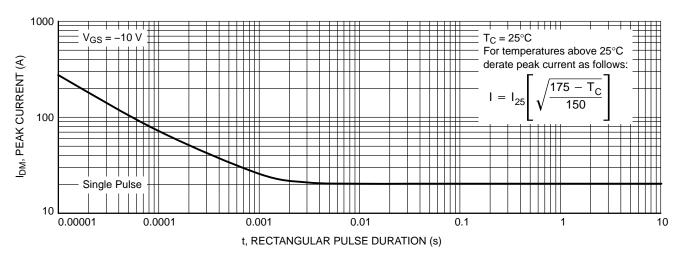


Figure 4. Peak Current Capability

TYPICAL CHARACTERISTICS

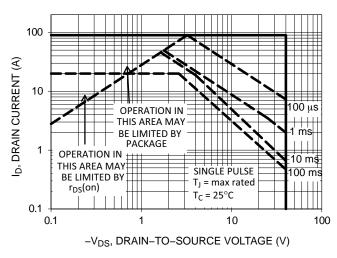
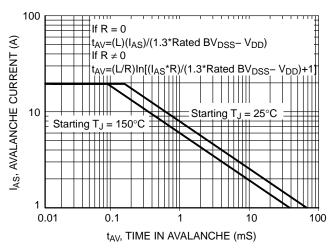


Figure 5. Forward Bias Safe Operating Area



Note: Refer to ON Semiconductor Application Notes AN7514 and AN7515

Figure 6. Unclamped Inductive Switching Capability

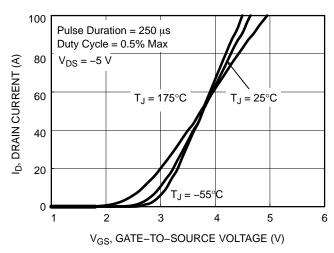


Figure 7. Transfer Characteristics

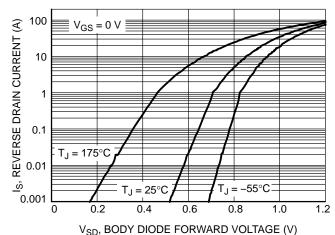


Figure 8. Forward Diode Characteristics

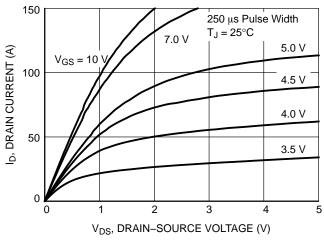


Figure 9. Saturation Characteristics

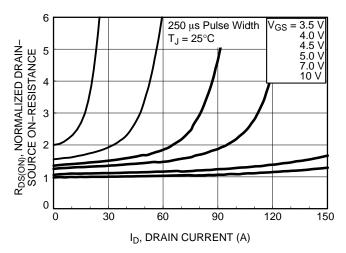
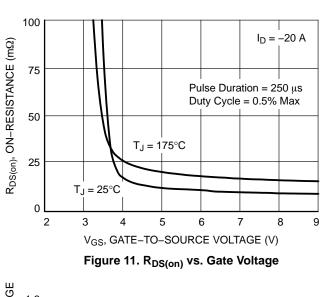


Figure 10. Normalized R_{DS(ON)} vs. Drain Current

TYPICAL CHARACTERISTICS



1.8

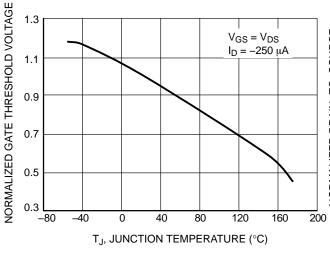
ID = -20 A

VGS = -10 V

ID = -20 A

VGS

Figure 12. Normalized R_{DS(on)} vs. Junction Temperature



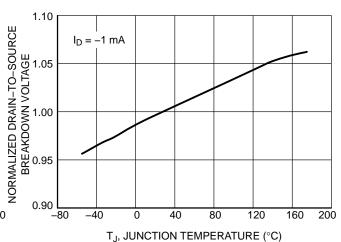
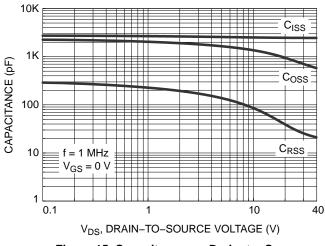


Figure 13. Normalized Gate Threshold Voltage vs. Temperature

Figure 14. Normalized Drain-to-Source Breakdown Voltage vs. Junction Temperature



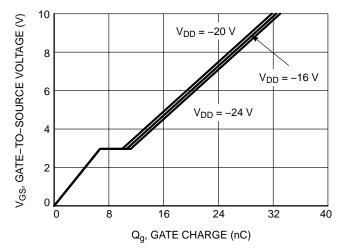
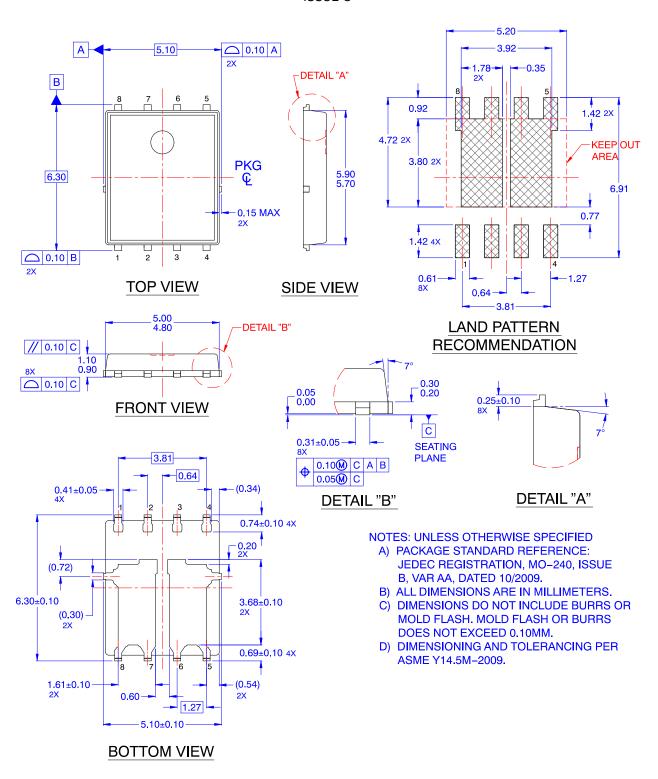


Figure 15. Capacitance vs. Drain-to-Source Voltage

Figure 16. Gate Charge vs. Gate-to-Source Voltage

PACKAGE DIMENSIONS

PQFN8 5X6, 1.27P CASE 483BL ISSUE O



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